

P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^d	Q _g (Typ.)			
- 30	0.011 at V _{GS} = - 10 V	- 11.6	22 nC			
	0.012 at $V_{GS} = -4.5 \text{ V}$	- 10				

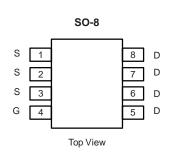
FEATURES

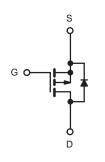
- Halogen-free According to IEC 61249-2-21 **Available**
- TrenchFET® Power MOSFET
- 100 % R_g Tested
 100 % UIS Tested





- · Load Switches
 - Notebook PCs
 - Desktop PCs





P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS \top	A = 25 °C, unless other	erwise noted			
Parameter	Symbol Limit		Unit		
Drain-Source Voltage		V _{DS}	- 30	V	
Gate-Source Voltage		V _{GS}	± 20	V	
	T _C = 25 °C		- 11.6		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	1 , 🗀	- 10.5		
Continuous Dialit Current (1) = 150 °C)	T _A = 25 °C	I _D	- 8.7 ^{a, b}		
	T _A = 70 °C		- 7.7 ^{a, b}		
Pulsed Drain Current		I _{DM}	- 40	A	
Continuous Courses Dunis Diedo Coursest	T _C = 25 °C		- 4.6		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.0 ^{a, b}		
Avalanche Current	1 0411	I _{AS}	- 20		
Single-Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	20	mJ	
	T _C = 25 °C		5.6		
Mayimum Dayor Dissination	T _C = 70 °C	ь —	3.6	w	
Maximum Power Dissipation	T _A = 25 °C	P _D	2.5 ^{a, b}	VV	
	T _A = 70 °C	1 -	1.6 ^{a, b}		
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	39	50	°C/W	
Maximum Junction-to-Foot	Steady State	R _{thJF}	18	22	C/VV	

- a. Surface mounted on 1" x 1" FR4 board.
- c. Maximum under Steady State conditions is 85 °C/W. d. Based on $T_{\rm C}$ = 25 °C.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	$\Delta V_{DS}/T_J$ $I_D = -250 \mu A$		- 31		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			5.5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	- 1.0		- 3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			± 100	nA	
Zama Oata Vallana Basis Osamast	I _{DSS}	V _{DS} = - 30 V, V _{GS} = 0 V			- 1		
Zero Gate Voltage Drain Current		V _{DS} = - 30 V, V _{GS} = 0 V, T _J = 55 °C			- 5	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 30			Α	
Durin Orania On Otata Basista and	D	V _{GS} = - 10 V, I _D = - 10 A	0.011				
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 7 A		0.012		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 10 A		23		S	
Dynamic ^b							
Input Capacitance	C _{iss}			1960		pF	
Output Capacitance	C _{oss}	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		380			
Reverse Transfer Capacitance	C _{rss}			325			
Total Cata Charra		$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -10 \text{ A}$		43	65		
Total Gate Charge				22	33	0	
Gate-Source Charge	Q_{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10 \text{ A}$		6		nC	
Gate-Drain Charge	Q_{gd}			11			
Gate Resistance	R _g	f = 1 MHz	0.3	1.3	2.5	Ω	
Turn-On Delay Time	t _{d(on)}			11	22		
Rise Time	t _r	V_{DD} = - 15 V, R_L = 3 Ω		13	25	1	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -5 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		32	50		
Fall Time	ì _f	1		9	18		
Turn-On Delay Time	t _{d(on)}			44	70	ns	
Rise Time	ì,	V_{DD} = - 15 V, R_L = 3 Ω		100	160		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong$ - 5 A, V_{GEN} = - 4.5 V, R_g = 1 Ω		28	50		
Fall Time	ì,]		15	30		
Drain-Source Body Diode Characterist	ics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 4.6	۸	
Pulse Diode Forward Current	I _{SM}	-			- 50	Α	
Body Diode Voltage	V _{SD}	$I_S = -2 \text{ A}, V_{GS} = 0 \text{ V}$		- 0.75	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			28	45	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1 2 A d1/d+ 400 A/: T 05 00		20	40	nC	
Reverse Recovery Fall Time	t _a	I _F = -2 A, di/dt = 100 A/μs, I _J = 25 °C		13		ns	
Reverse Recovery Rise Time	t _b			15			

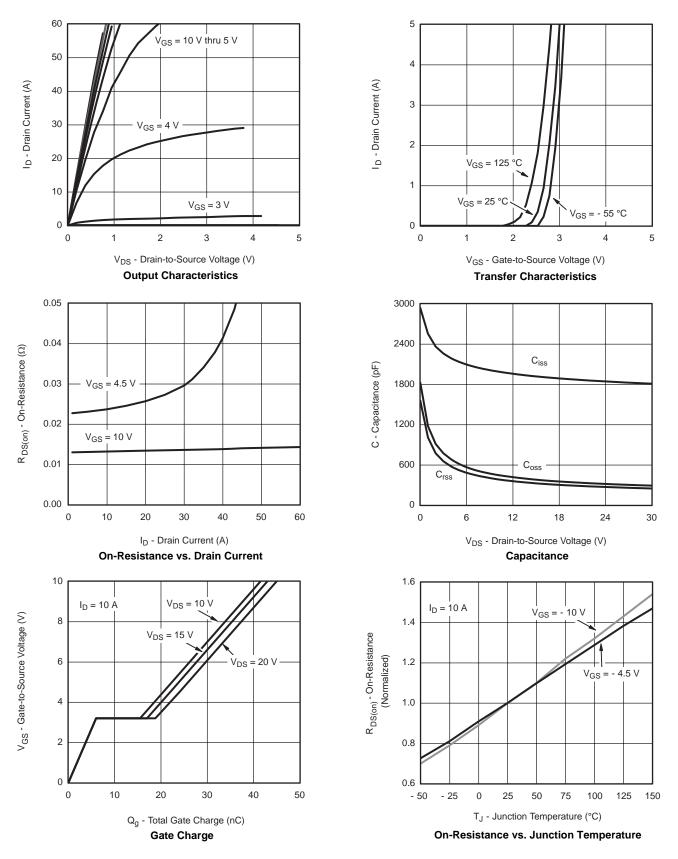
Notes:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

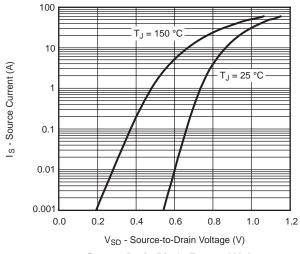
a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$

b. Guaranteed by design, not subject to production testing.

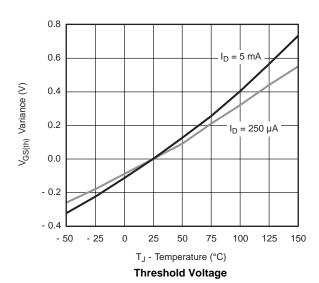


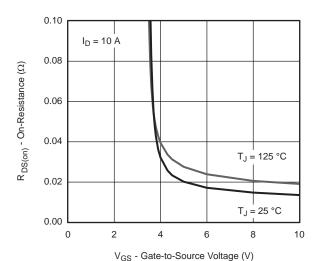




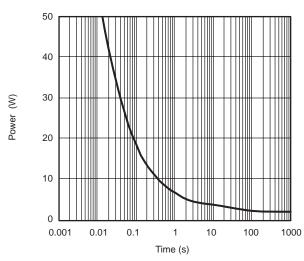


Source-Drain Diode Forward Voltage

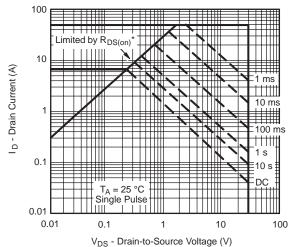




On-Resistance vs. Gate-to-Source Voltage



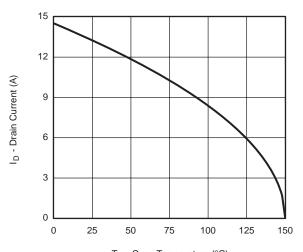
Single Pulse Power, Junction-to-Ambient



* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

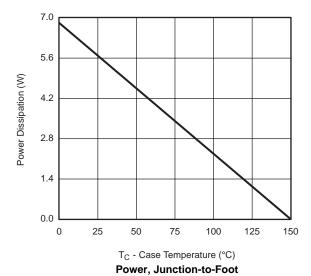
Safe Operating Area

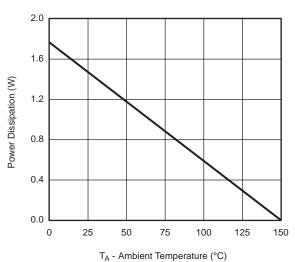




 $T_{\mbox{\scriptsize C}}$ - Case Temperature (°C)

Current Derating*

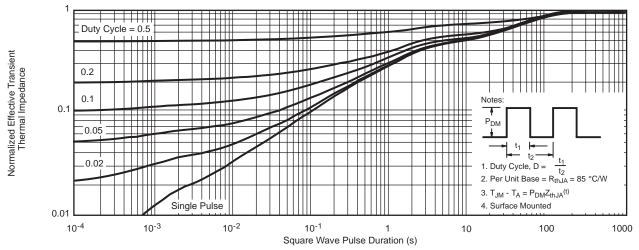




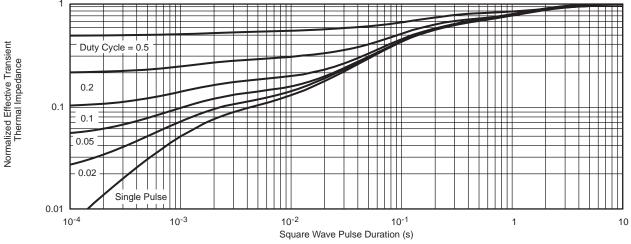
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient



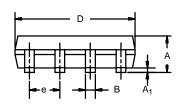
Normalized Thermal Transient Impedance, Junction-to-Foot

服务热线:400-655-8788 6



SOIC (NARROW): 8-LEADJEDEC Part Number: MS-012







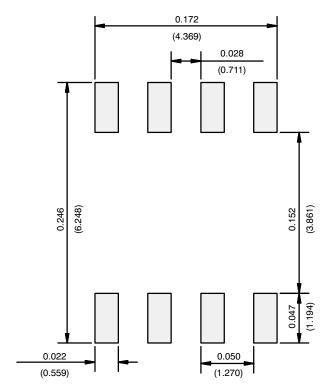
	MILLIM	IETERS	INC	HES	
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27	BSC	0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FCN: C-06527-Rev I 11-Sen-06					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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